

Umberto Celano is a Senior Research Scientist at imec (Belgium), currently visiting the Geballe Laboratory for Advanced Materials at Stanford University (USA). He received his Ph.D. in Physics from the University of Leuven (KU Leuven) in December 2015. His research has established a novel three-dimensional nanoscale imaging technique that combines sensing with sub-nm material removal to study materials in confined volumes. Umberto is the recipient of the Rogen A. Haken Best Paper Award at IEDM (2013) and has authored or co-authored 50+ papers in international journals and conference proceedings. He works with the metrology working-group in the International Roadmap for Devices and Systems (IRDS) and he is a member of the early carrier editorial board of Nano Letters. Previously, Umberto received his B.Eng. in Electronic Engineering and a M.Sc. degree in Nanoelectronics with honors from the University of Rome Sapienza, Italy.